

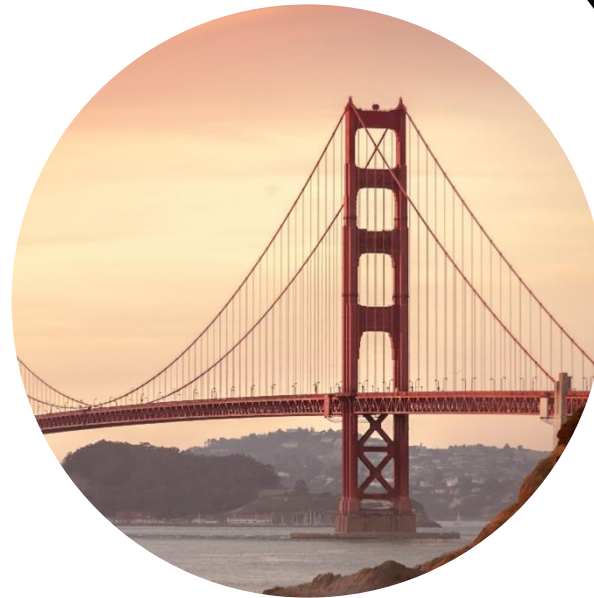
Deep Learning for Characterization of Deformation Induced Damage

U. Kerzel, S. Medghalchi, C. Kusche, T.
Al-Samman, S. Korte-Kerzel
TMS 2021 – virtual conference



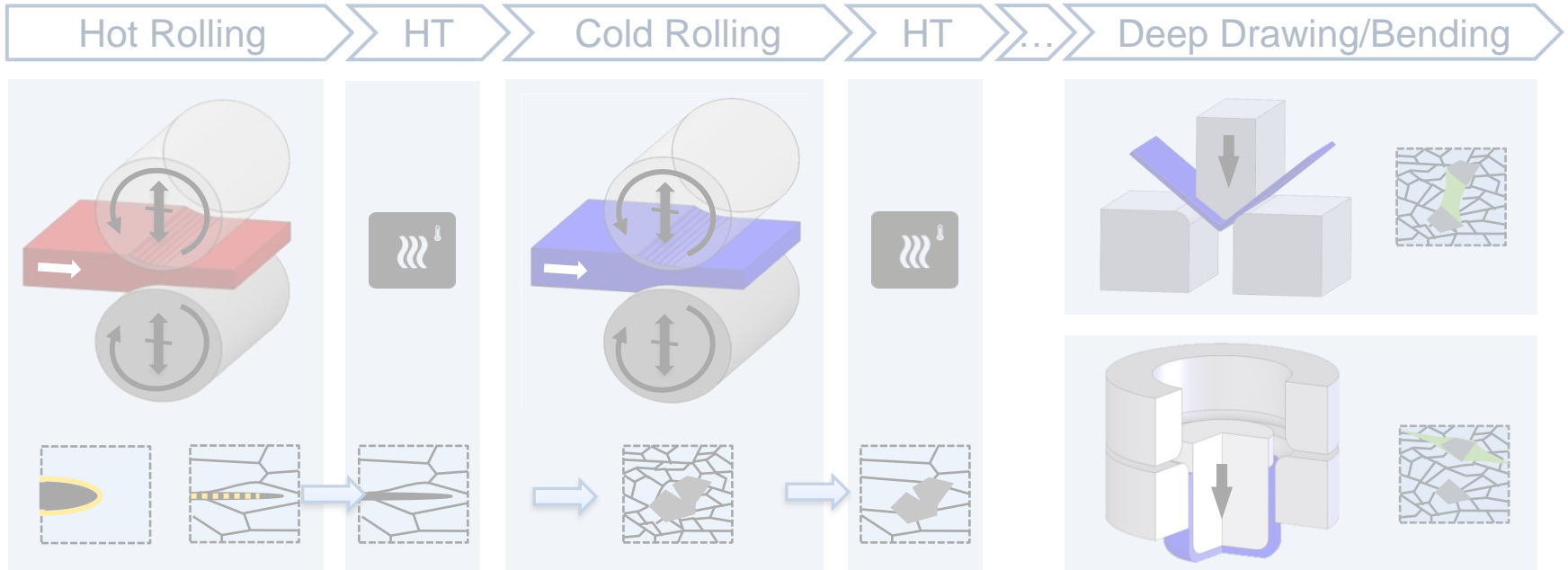


Why Steel?

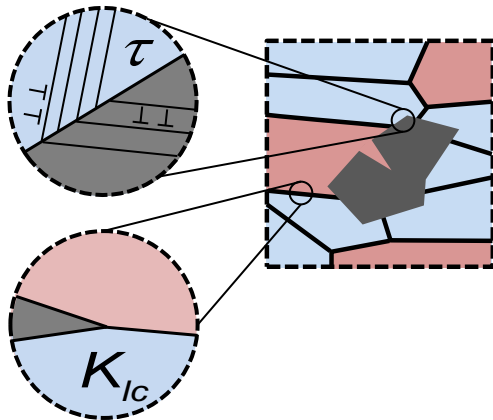


One of our most versatile materials.

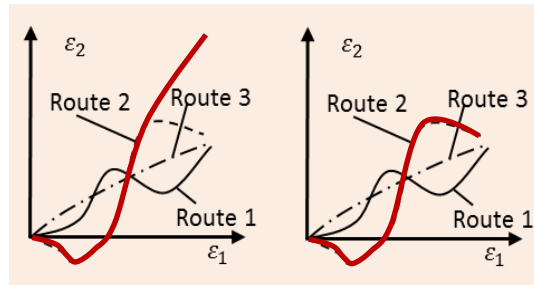
Important for industrial applications:
Dual Phase steel (e.g. DP800)



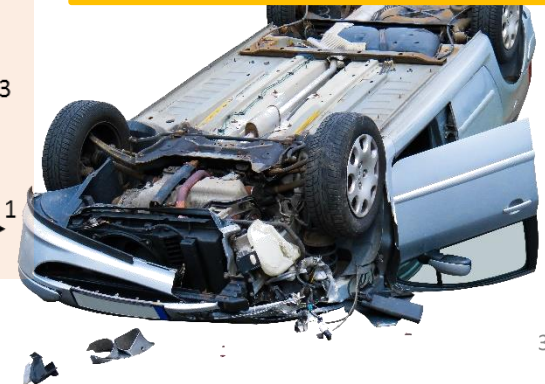
Damage Mechanisms



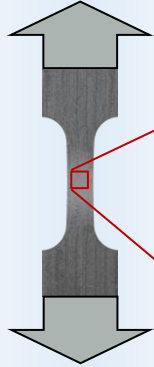
Better Processes



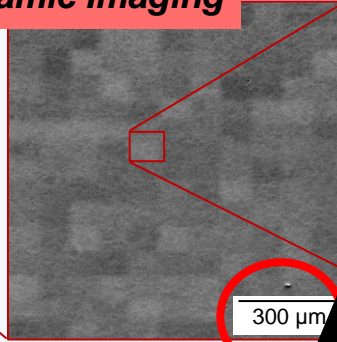
Better Materials



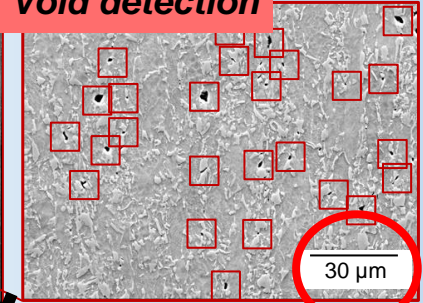
Deformation



Panoramic Imaging



Void detection



N.B. 2 orders of magnitude



apply stress on material sample



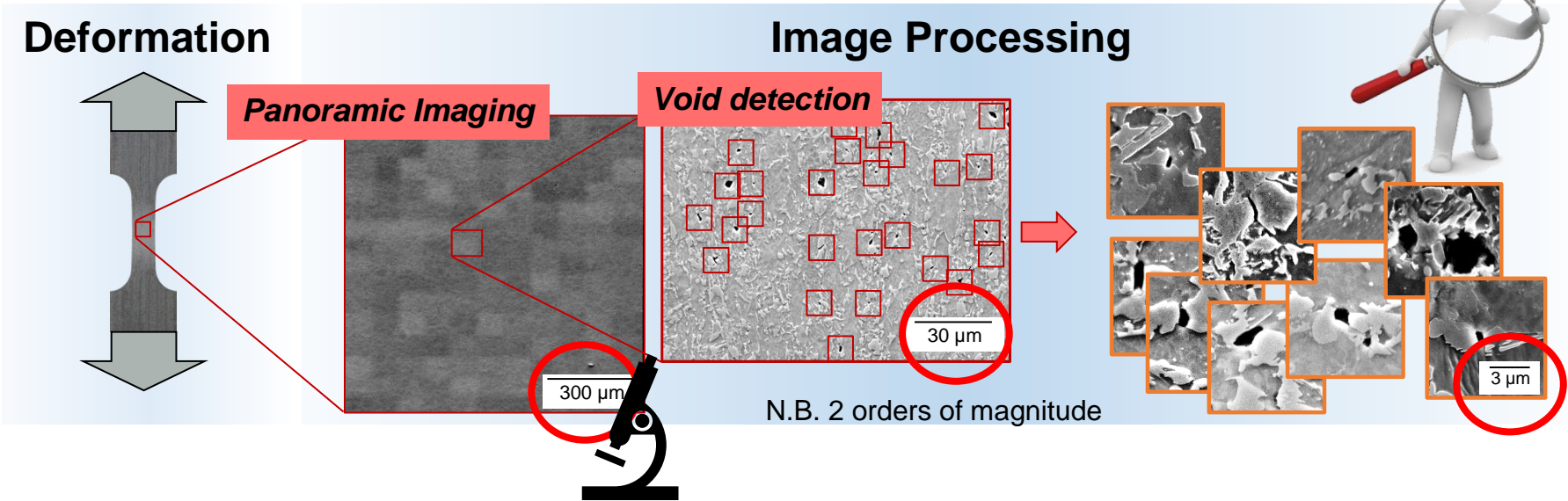
electron microscope imaging



Damage localization



manual image analysis



apply stress on material sample



electron microscope imaging



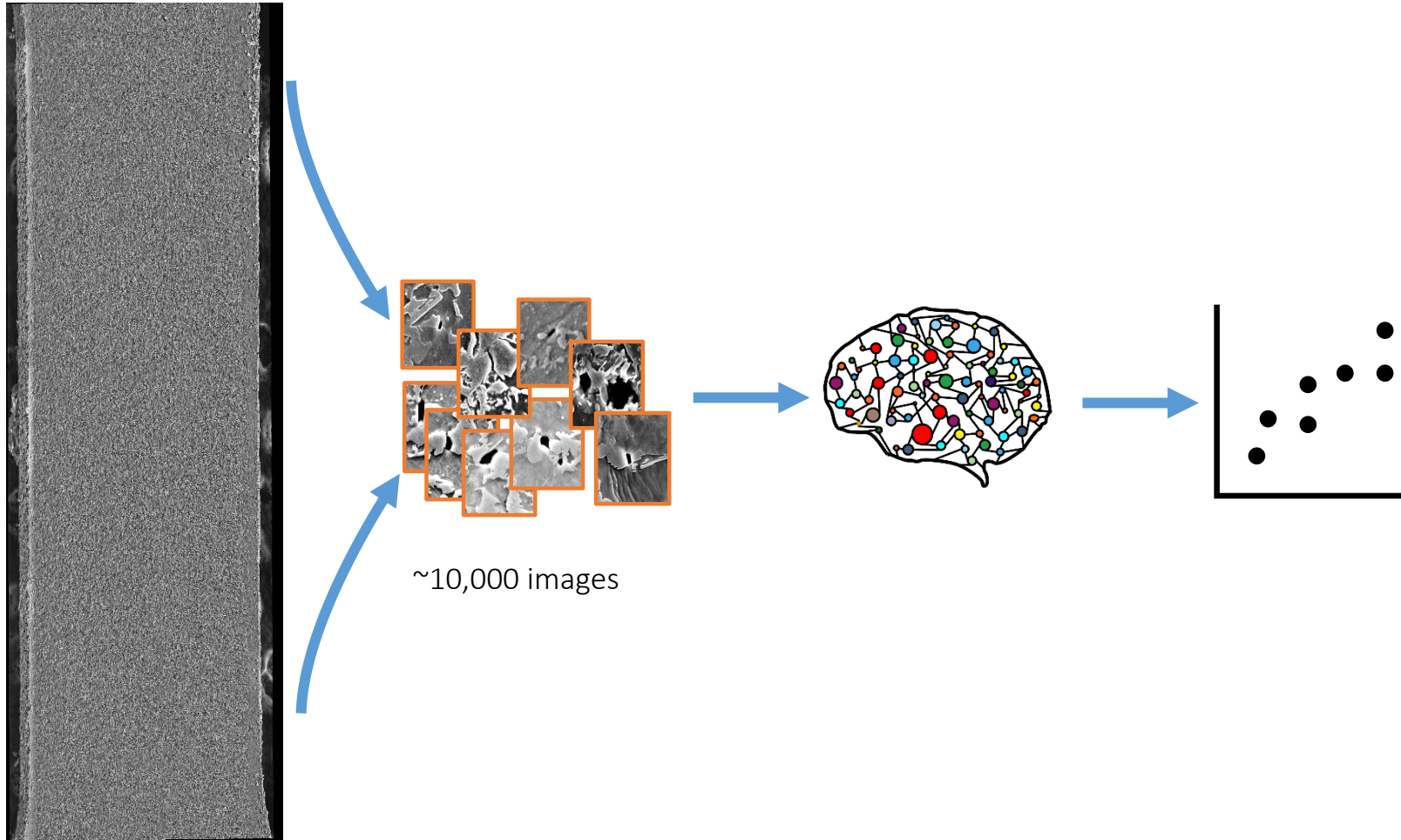
Damage localization



manual image analysis

- Detailed understanding of individual damage sites & mechanisms
- Manual approach does not allow statistical analysis

→ Automate image analysis with Deep Learning



Obtain high-res panoramic image

Automated damage localization

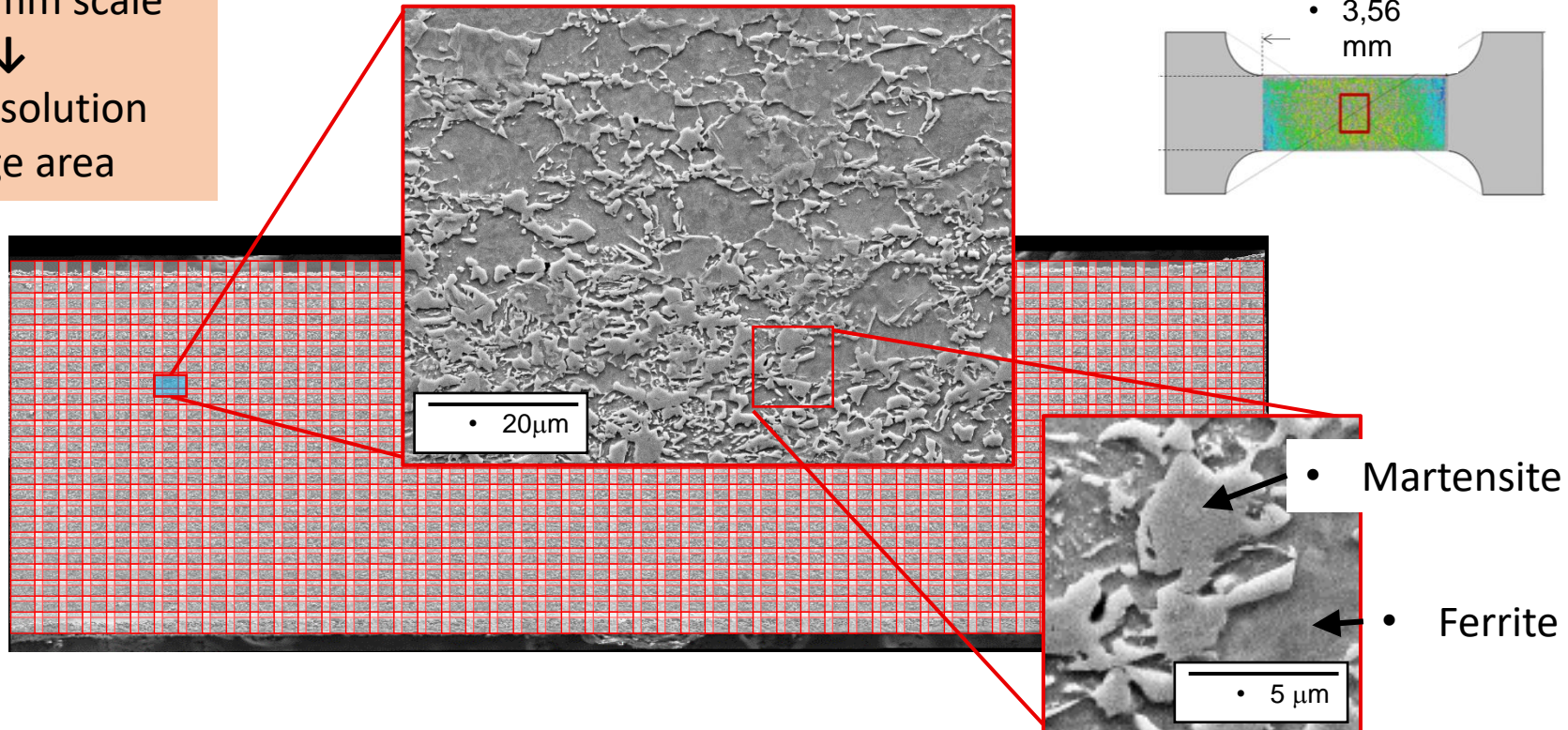
Deep learning: Damage ID

Statistical Analysis

Heterogeneous at
< μm – mm scale



High resolution
+ large area

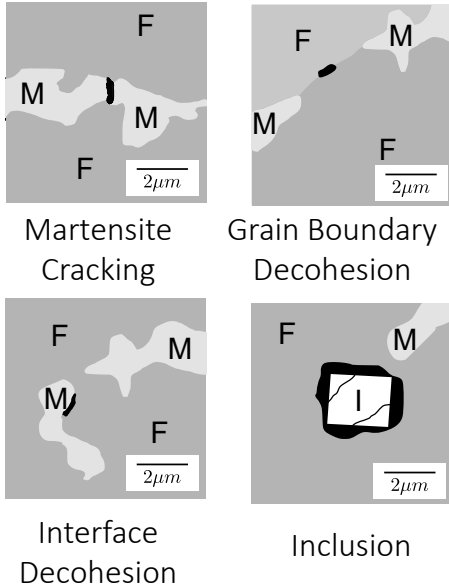


High-res panoramic image of a large sample space

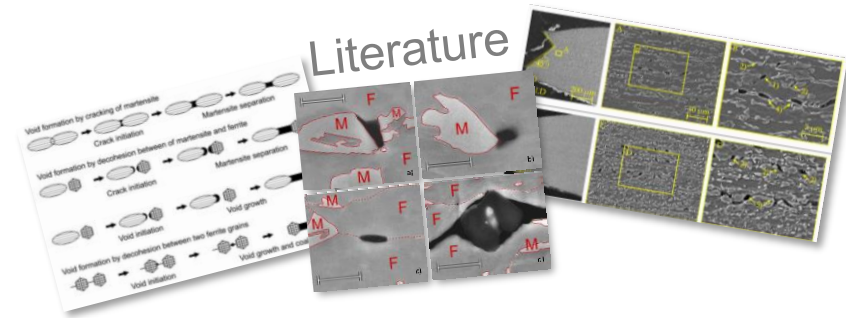
→ Handle many images

- OK for PoC
- Setup data infrastructure for continued analysis (Image + Metadata) (e.g., Mongo DB)

Supervised learning: Require labelled images – definition of semantic classes?

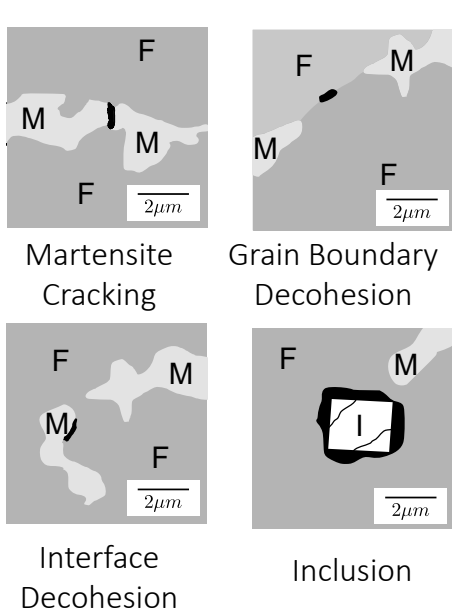


Step 1: Relevant Literature

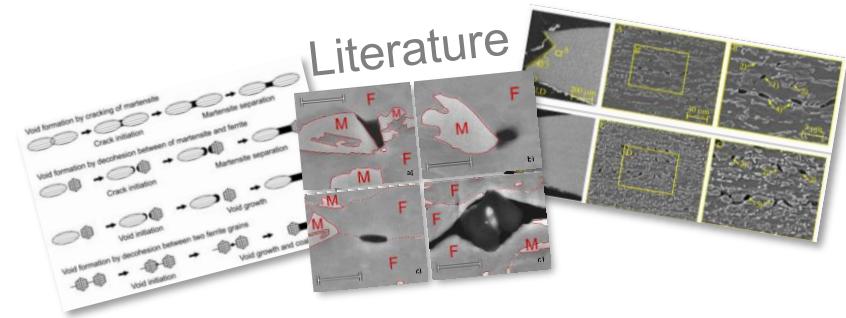


Hoefnagels, J.P.M., et al. (2015) || J Mater Sci 50(21) 6882
 Azuma, M. (2013) PhD thesis, TU Denmark || Heibel, S. et al. (2018) Materials 11, 761

Supervised learning: Require labelled images – definition of semantic classes?



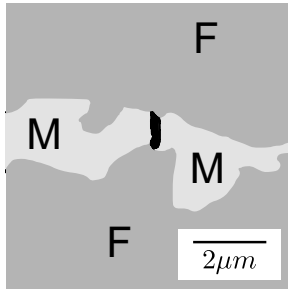
Step 1: Relevant Literature



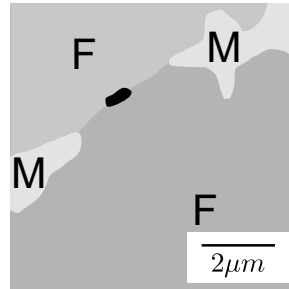
Hoefnagels, J.P.M., et al. (2015) || J Mater Sci 50(21) 6882
 Azuma, M. (2013) PhD thesis, TU Denmark || Heibel, S. et al. (2018) Materials 11, 761

Step 2: Revise & Clarify Class Definitions

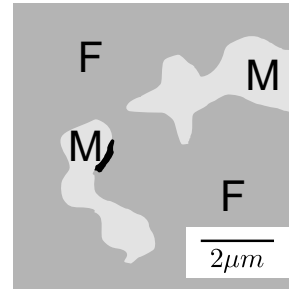
- Class definitions suitable for “clear cut” cases (what is normally looked at)
- Many “in-between” cases
 - Important for statistical analysis
 - Consolidate class labels with multiple experts



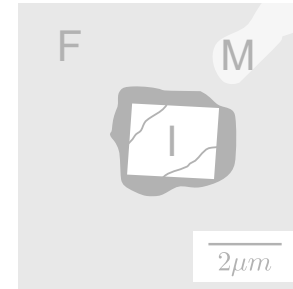
Martensite Cracking



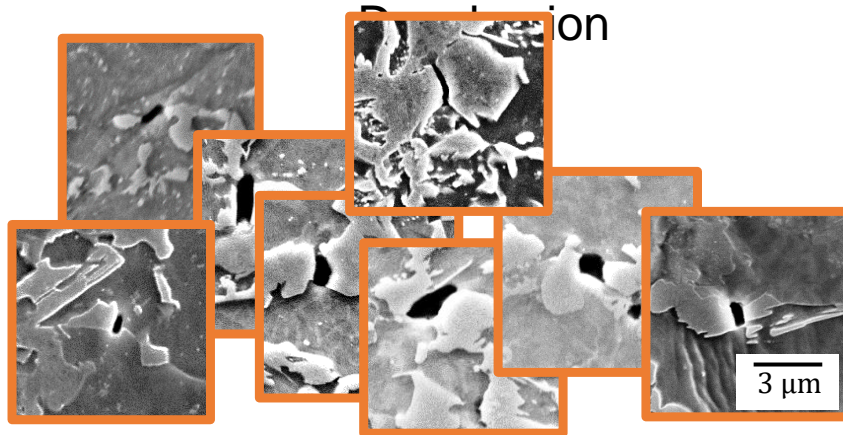
Grain Boundary



Interface Decohesion

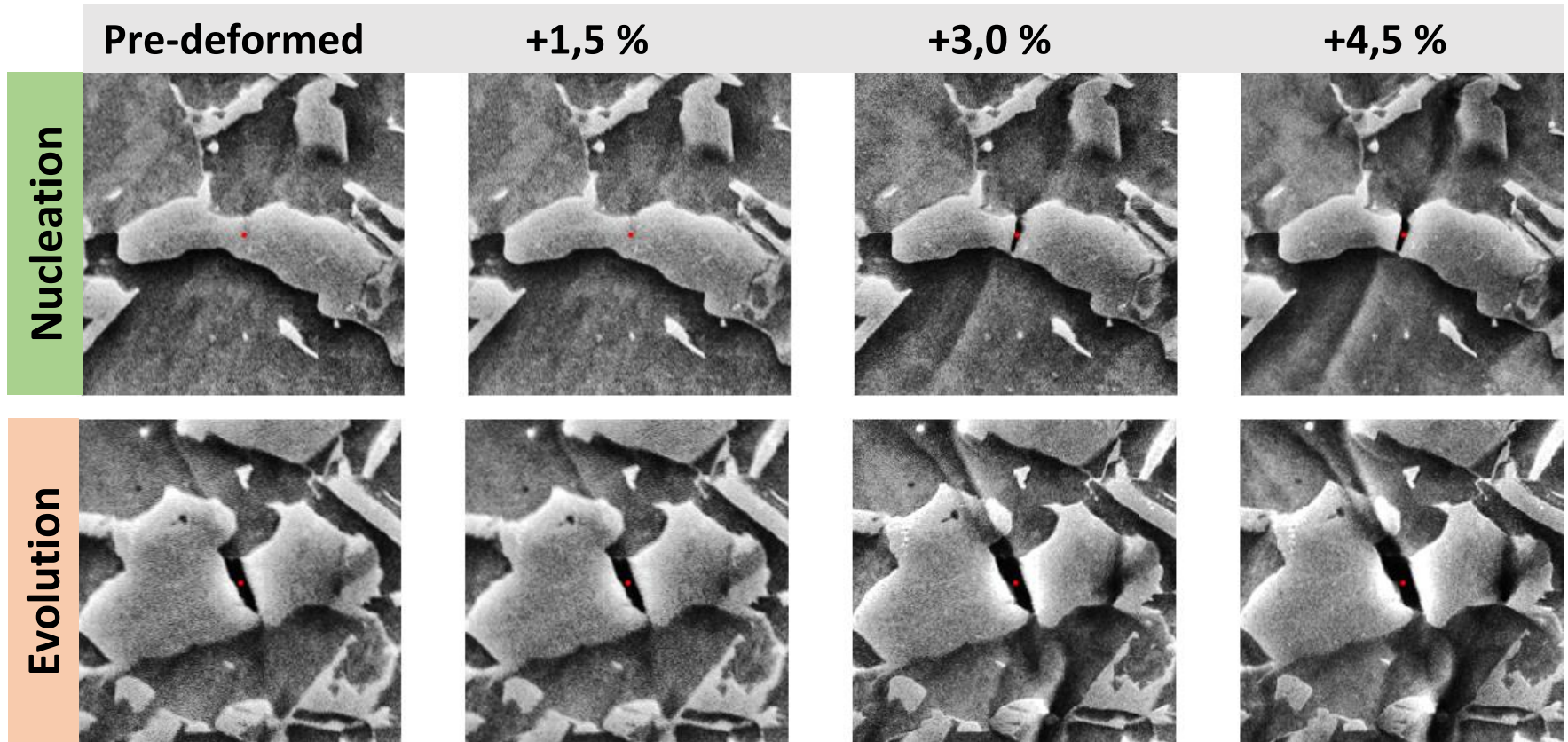


Inclusion



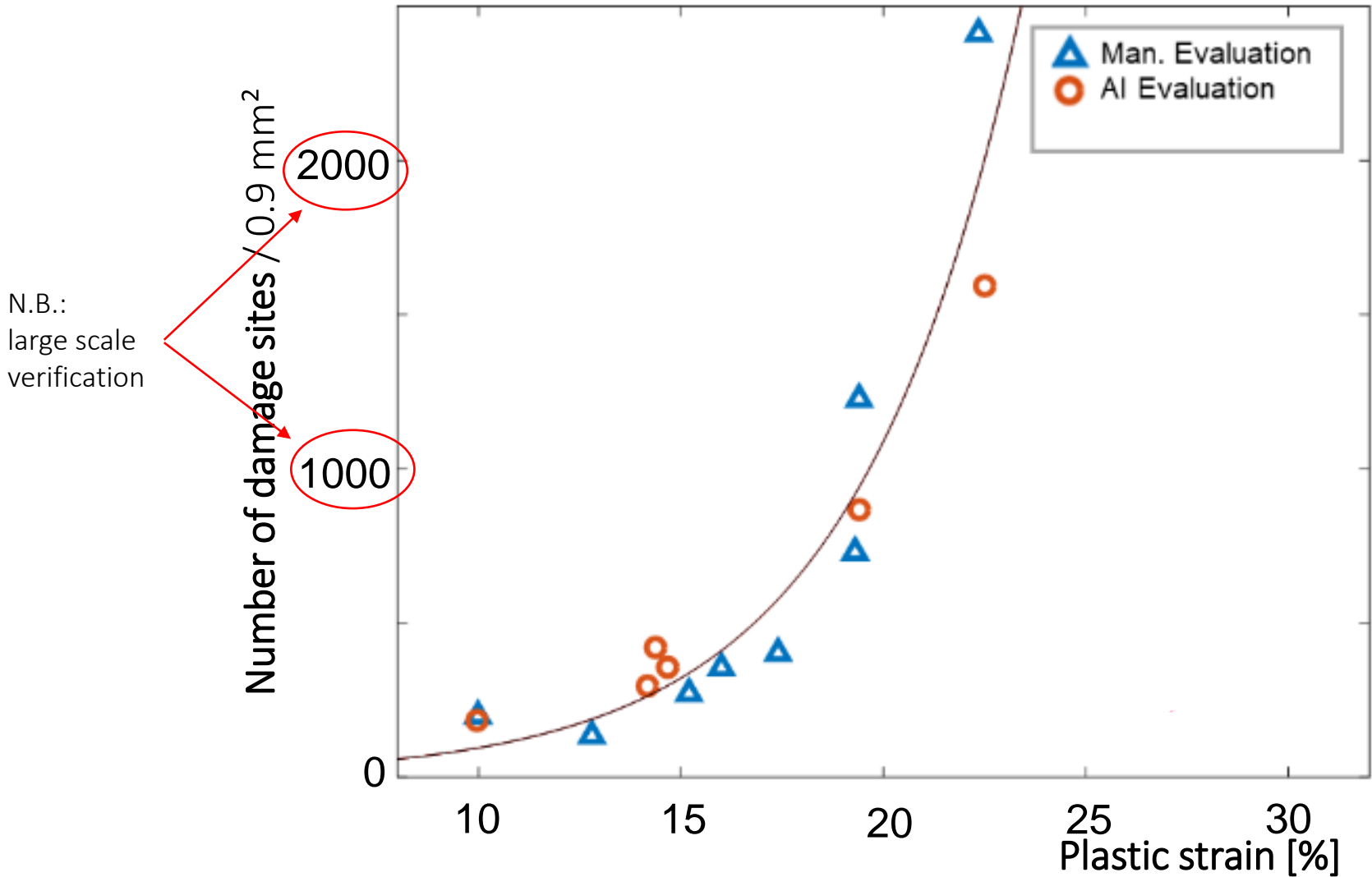
Panoramic imaging
→ *big data*

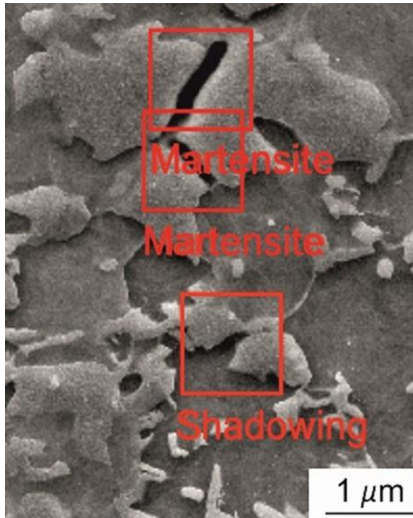
Kusche et al. (2019) PloS one 14 (5), e0216493



Kusche et al. (2019) PloS one 14 (5), e0216493

Compare Deep learning results with manual expert verification

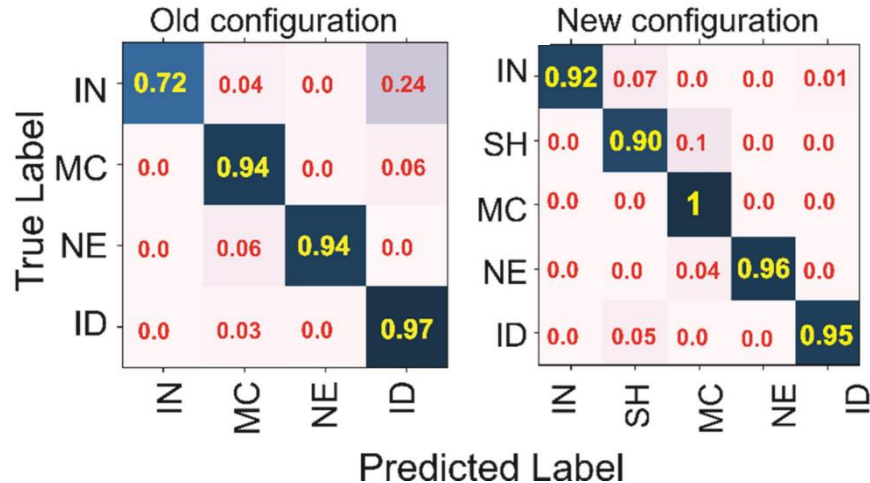
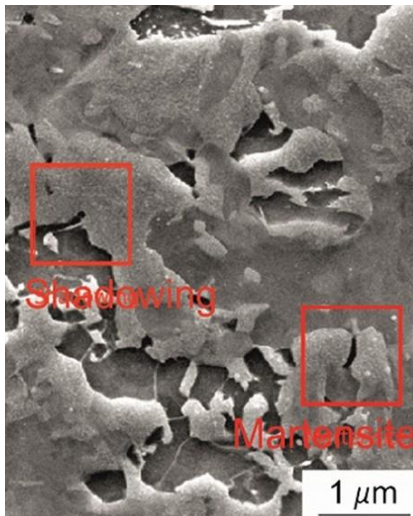




Imaging artifacts increase mis-classification

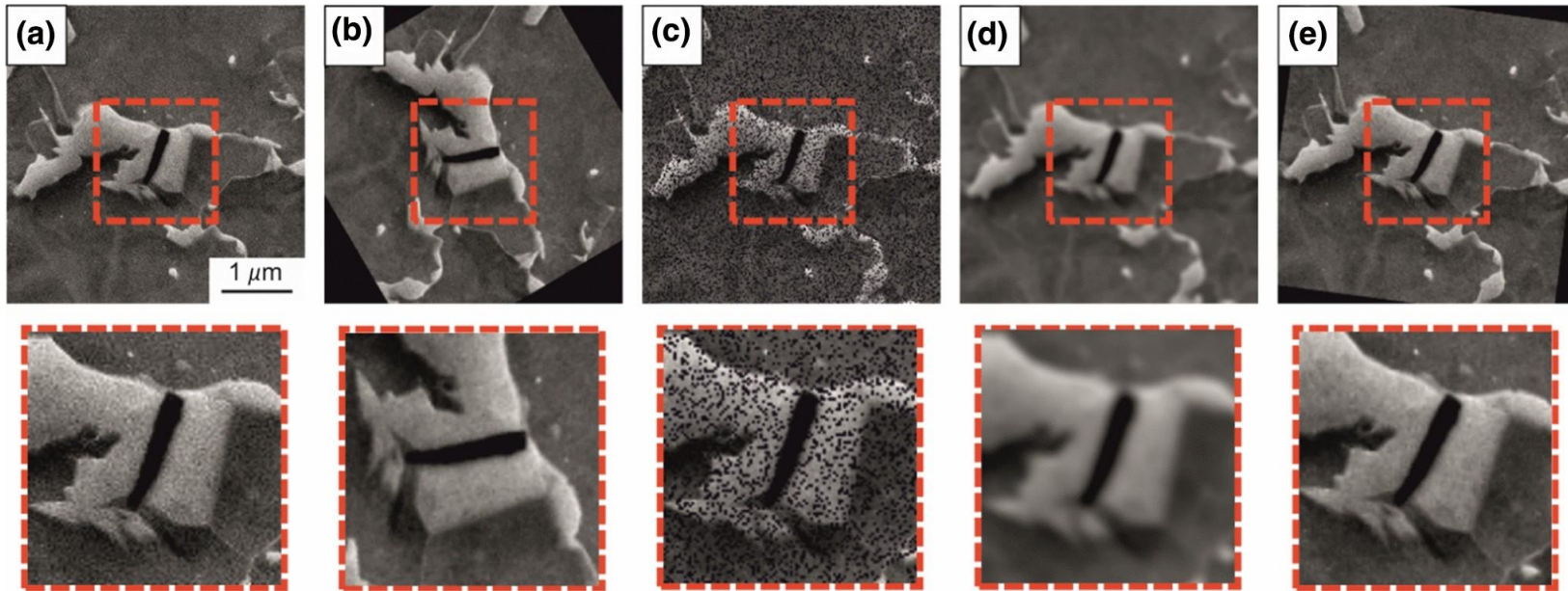
- In particular: shadows of e-beam on 3D sample structure
- Extend semantic classes: add artefact “SH” (shadow) as class
 - Significant increase in performance
 - So far: major artefact – but monitor for new preparations

Data *doesn't* speak for itself!



Supervised Learning:

- Requires labelled images *representative* of sample for inference.
- Costly to obtain: Manual work by experts
- Challenge for generalizability – example: uniaxial to biaxial stress
- Approach: image augmentation
 - Rotation, pixel dropout, blur, shear



Augmentations:

(a) original image, (b) random rotation, (c) random pixel dropout, (d) Gaussian blur, and (e) random shear.

Beyond PoC: Organize data systematically

Store data (images) *and* metadata:

- Date, time, location, sample ID
- Experimental conditions of imaging equipment
 - Microscope settings,
 - beam acceleration,
 -
- Sample details
 - Details about the sample, manufacturing process, ...
 - Preparation prior to imaging (etching,)
 - ...
- Image relationship
 - Original image as recorded
 - Image after enhancement
 - Stitched panorama
 - Identified image location (incl. location details)
 - ...
-



No community-wide infrastructure available.

mongoDB seems promising candidate:

- Mature technology
- Open source
- Community to enterprise option
- Cloud scaling to planetary scale possible
- Connectors
- PyMongo for Python access

Supervised learning is the greatest thing (after sliced bread):

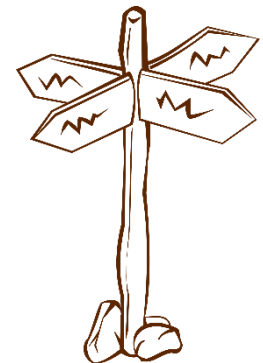
- Machine learning algorithm learns desired mapping: labelled images to label
- Semantic classes well defined:
 - Hand-crafted and verified by experts in the field
 - Artifacts can be included in well defined way
- Data doesn't speak for itself:
 - Verify semantic classes
 - Include expert knowledge in image labels

.... But: Doesn't scale

- New data need to be labelled manually
- Data labelling doesn't get much faster with time
- Additional people: expert training required.

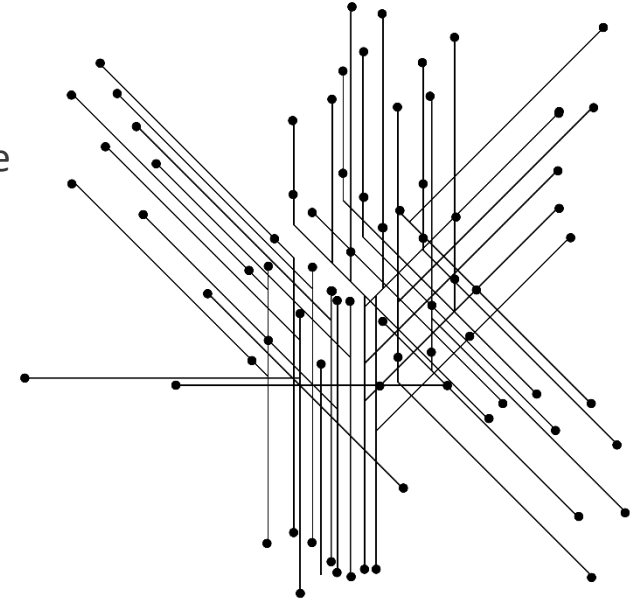
→ explore further options:

Deep clustering, self-supervised, semi-supervised, semi-self supervised, contrastive learning, ...



Representation Learning + Clustering

1. Use deep convolutional neural networks (CNN) to extract image features
 2. Use clustering (e.g. k-means) to group images into classes
- Little to no labelled data required
 - CNN are not explainable – decision boundaries do not match well with expert analysis
 - High and hard to control risk to learn artefacts instead of semantic classes.
 - Number of clusters: free parameter



Examples:

- Deep Adaptive Clustering (J. Chang et al, ICCV 2017)
- DeepCluster (M. Caron et al., ECCV 2018, arXiv: 1807.05520)
- DeeperCluster (M. Caron et al. ICCV 2019, arXiv: 1905.01278)
- Deep Image Clustering With Spatial Transformer (Th. V. M. Souza et al., ICANN 2019, arXiv: 1902.05401)
- ClusterFit (X. Yan et al., IEEE/CVF CV 2020, arXiv: 1912.03330)
- SCAN (W. v. Gansbeke et al, ECCV 2020, arXiv: 2005.12320)
- Self-labelling via simultaneous clustering and representation learning (Y. Asano et al, ICLR 2020, arxiv: 1911.05371)
- In materials science: R. Cohn & E. Holms (2020), arXiv: 2007.08361)

Intuition: Reduce dependency on labelled images
Split training into two steps:

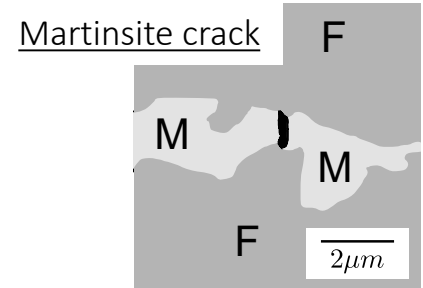
- Pre-train network with a suitable “pretext” task
- Fine-tune network with labelled images on actual task.

Idea:

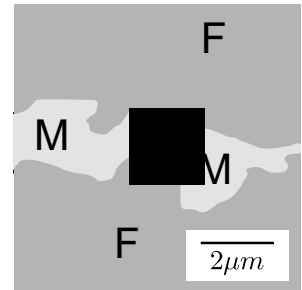
- Pretext task is something humans could do – but computers can do without human input
 - Pretext learns general representations
- Need much fewer labelled images once pretext task is trained
 - Downstream learns specifics for the actual task.

Challenges:

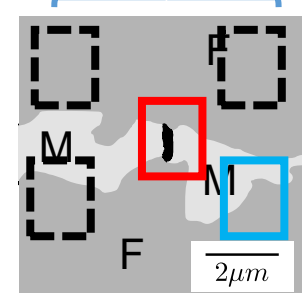
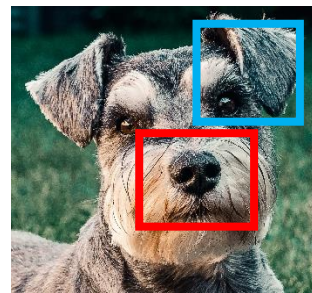
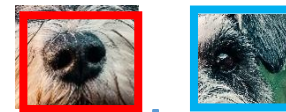
- Define a suitable pre-text for electron microscope imaging
 - Typically: colorization, position in image, fill a gap,...
 - Material science...?
 - Networks at high risk to learn artefacts in pretext task
 - Scratches, blurs, watermarks, aberrations, ...
- (M. Minderer et al. “Automatic shortcut removal for self-supervised representation learning.” PMLR, 2020, arXiv:2002.08822)



Learn to fill the gap?



Learn placement ?



Possible Avenues:

- X. Zhai, et al. “S4l: Self-supervised semi-supervised learning.” IEEE/CVF 2019, arXiv: 1905.03670
- J. Grill, et al. “Bootstrap your own latent: A new approach to self-supervised learning.” arXiv: 2006.07733
- K. Sohn et al. “FixMatch: Simplifying Semi-Supervised Learning [...]” NeurIPS 2020, arxiv: 2001.07685

Variant: Contrastive Learning: Maximize similarity / difference in image pairs

- SimCLR: T. Chen et al. “A Simple Framework for Contrastive Learning of Visual Representations” ICML 2020, arXiv: 2002.05709
- MoCo: K. He et al. “Momentum Contrast for Unsupervised Visual Representation Learning” CVPR 2020, arXiv: 1911.05722
- PIRL: I. Misra et al. “Self-Supervised Learning of Pretext-Invariant Representations” IEEE/CVF 2020, arXiv: 1912.01991
- A. Oord et al. “Representation Learning with Contrastive Predictive Coding” arXiv: 1807.03748

Key Insights:

(A Critical Analysis of Self-Supervision, or what we can learn from a single image, Y. Asano et al., ICLR 2020)

- *“First, we show that as little as a single image is sufficient, when combined with self-supervision and data augmentation, to learn the first few layers of standard deep networks as well as using millions of images and full supervision “*
- Deeper layers: *“For these, self-supervision remains inferior to strong supervision even if millions of images are used for training. Our finding is that this is unlikely to change with the addition of more data.”*

Deep Learning opens the door to statistical analysis in Materials Science

- Large scale damage identification with high accuracy
- Enables analysis of statistical effects & damage evolution under strain.

Significant challenges remain:

- Damage class definitions – underlying dominant mechanism of damage evolution
- Data handling and metadata
- Supervised learning most accurate and unlikely to be (fully) replacable
 - Large scale image labelling prohibitively costly
 - Many potential avenues to pursue:
 - representation learning + clustering, semi/self-supervised learning, contrastive learning,...
 - As of now: unclear which path most promising for damage analysis

Exciting opportunity for materials science to enter the age of large scale statistical analysis.

